

[54] ATOMIC ABSORPTION SPECTROPHOTOMETER

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[52] U.S. Cl. D10/46

[58] Field of Search D10/46; D24/1.1; 356/319, 326, 325; 250/428

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[57] CLAIM

The ornamental design for a atomic absorption spectro- photometer, as shown.

DESCRIPTION

FIG. 1 is a front, top and left side perspective view of a atomic absorption spectrophotometer showing our new design; FIG. 2 is front elevational view thereof; FIG. 3 is a right side elevational view thereof; FIG. 4 is a top plan view thereof; FIG. 5 is a bottom plan view thereof; FIG. 6 is a left side elevational view thereof; and FIG. 7 is a rear elevational view thereof.

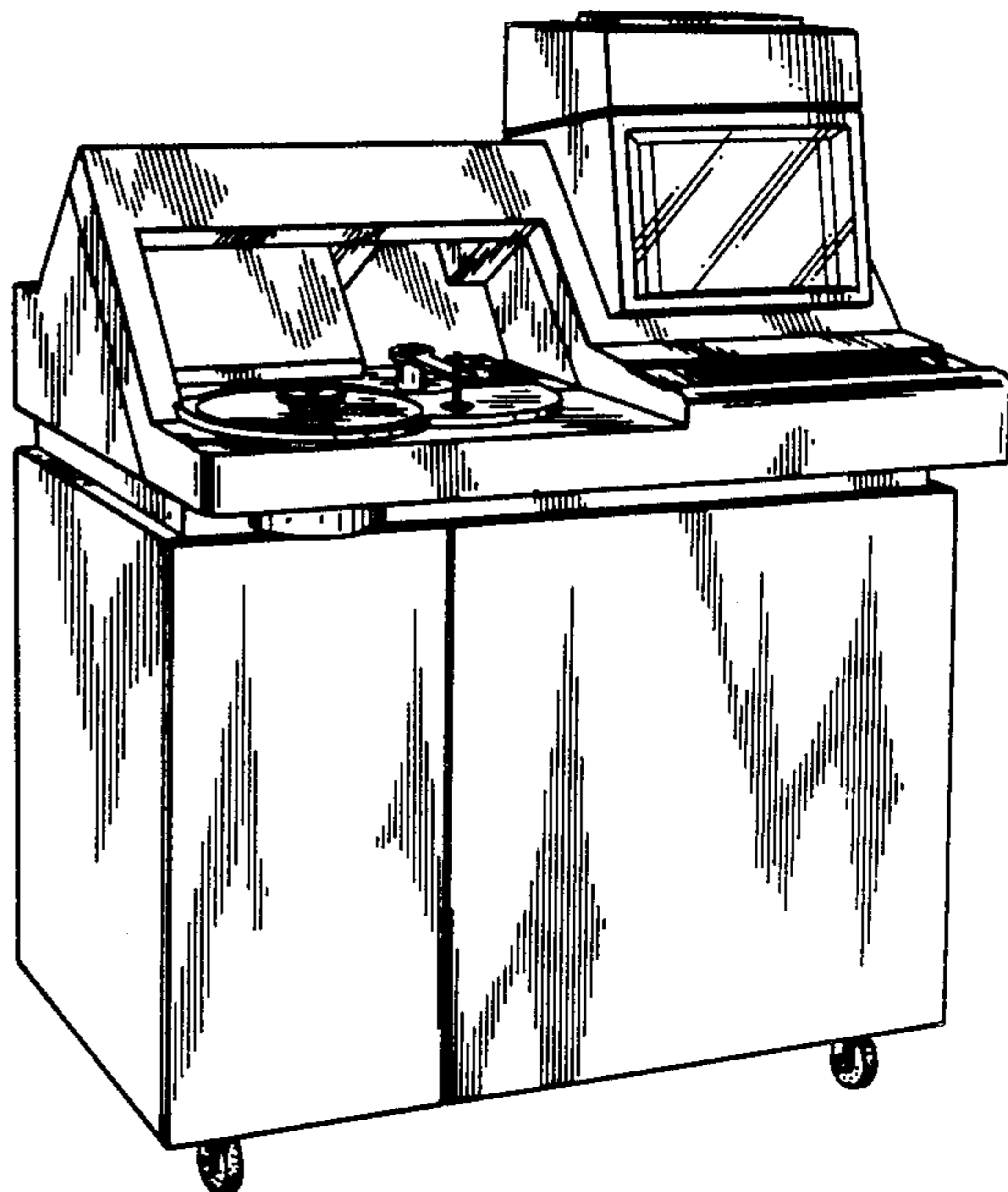


FIG. 1

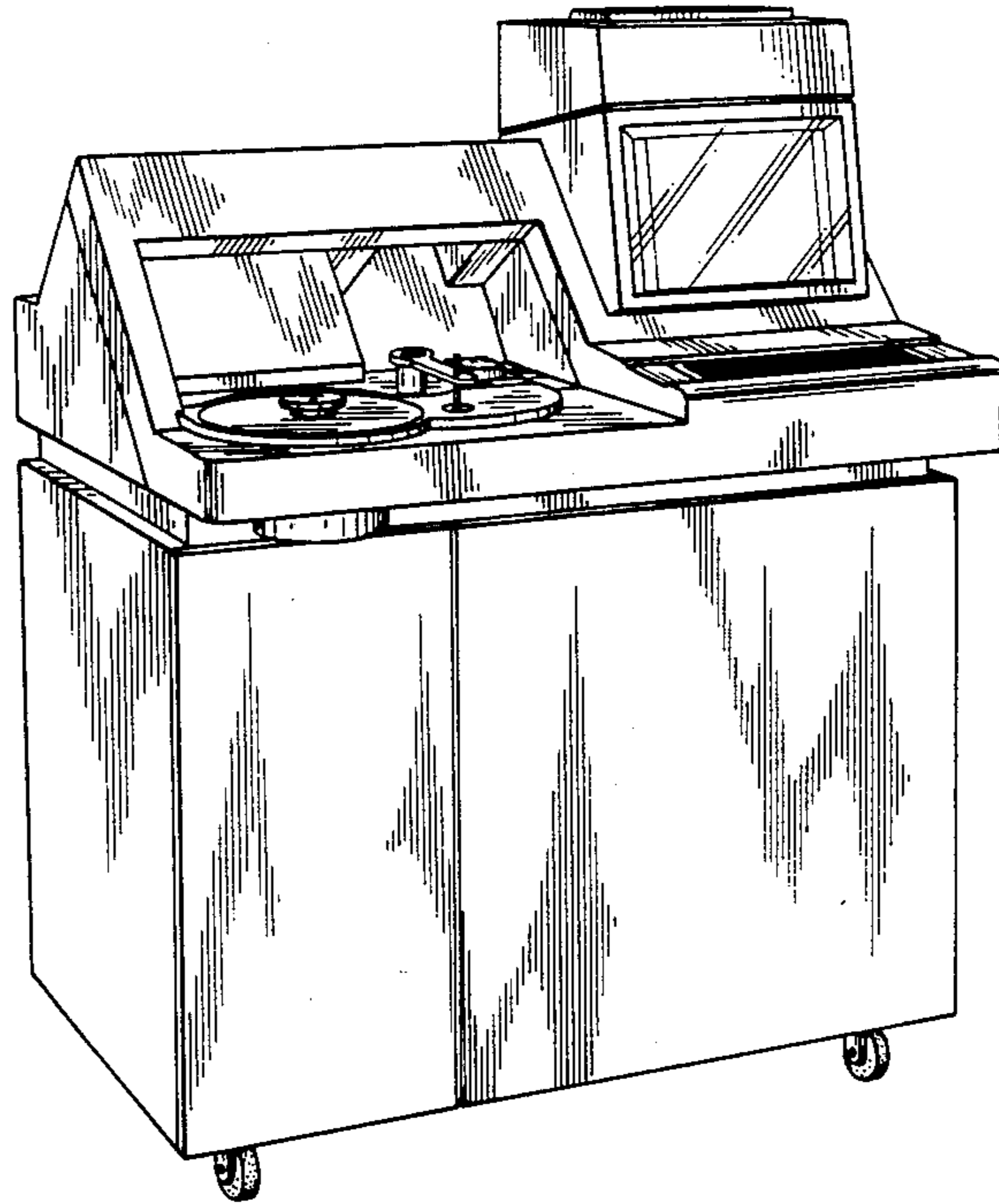


FIG. 2

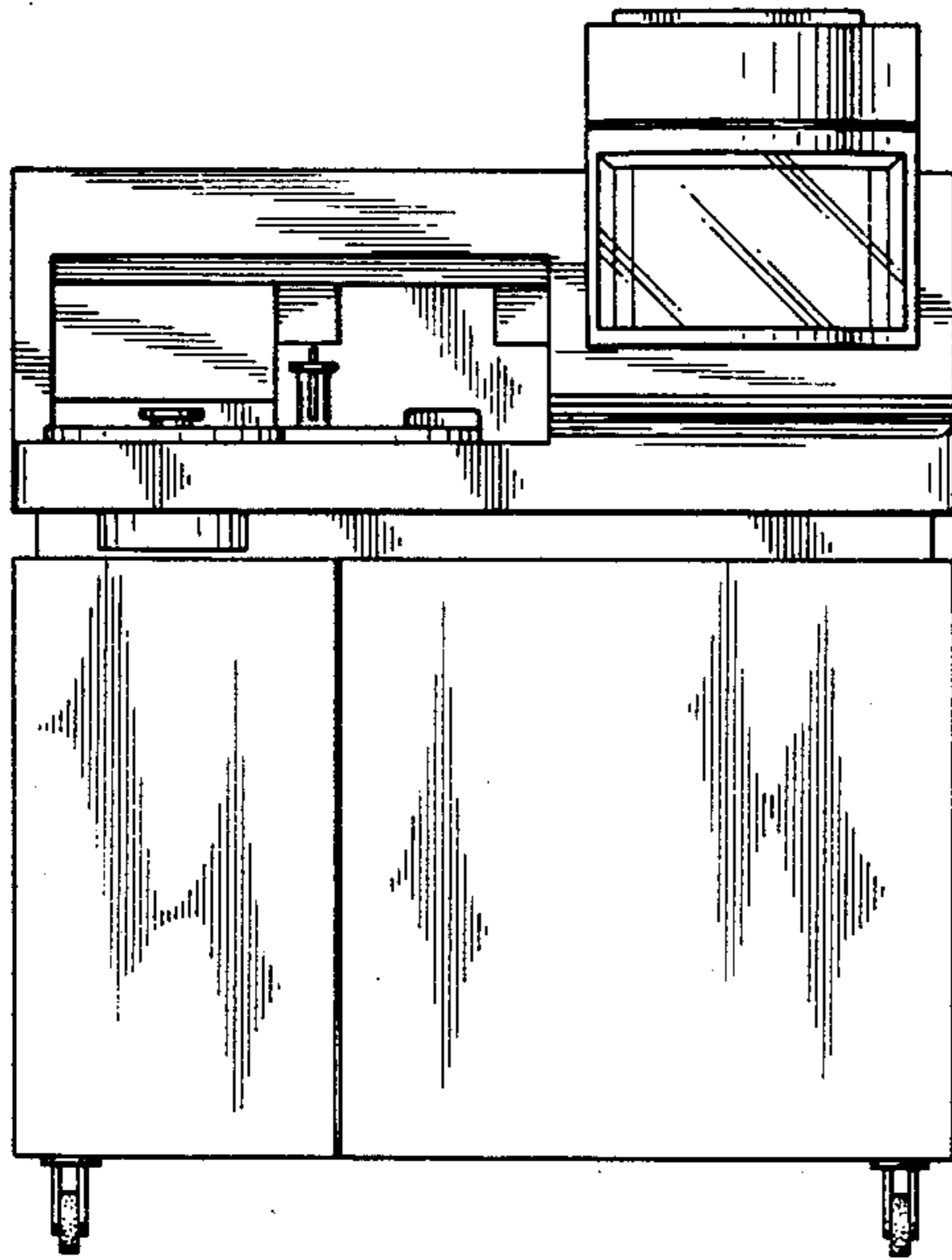


FIG. 3

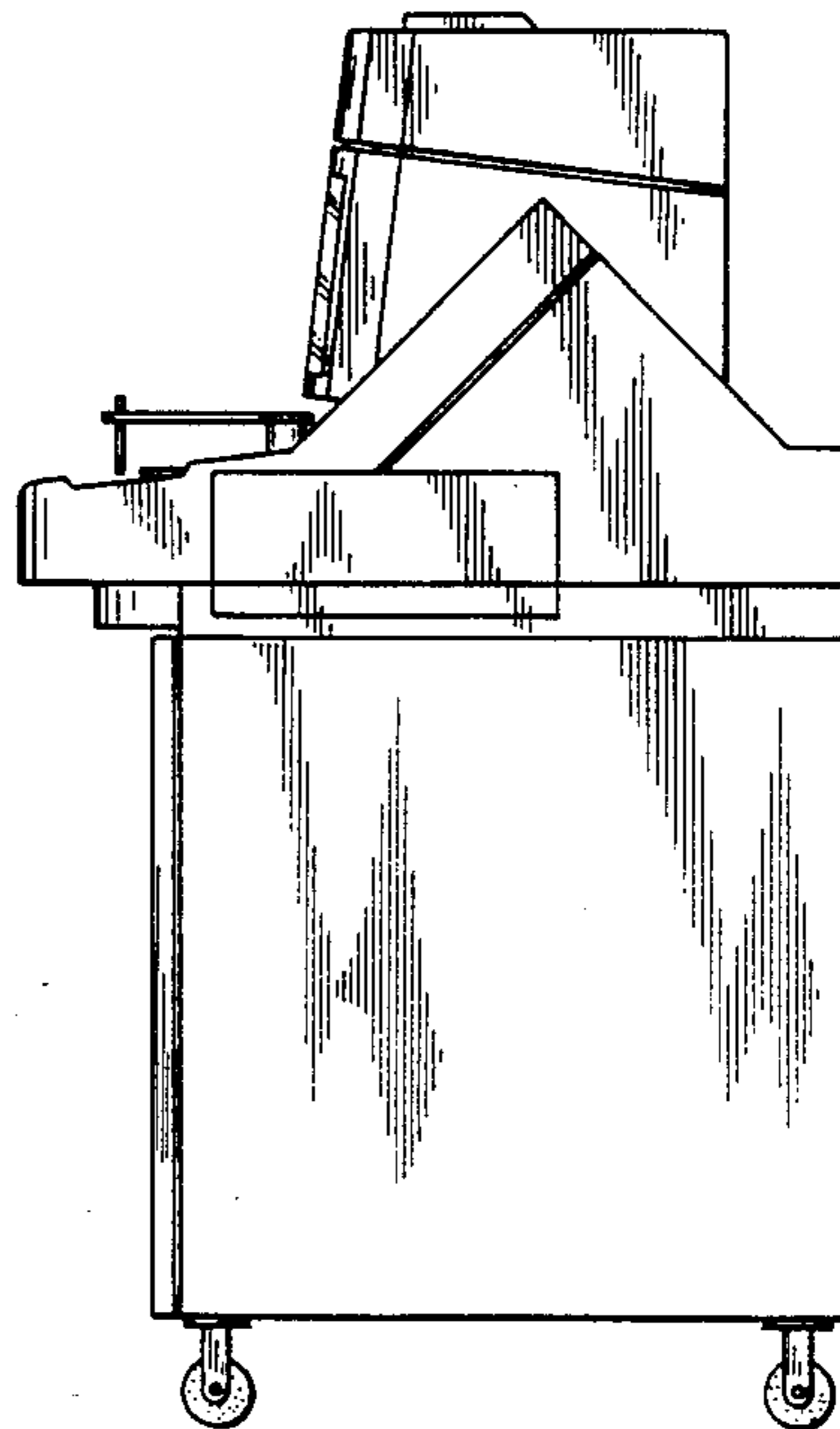


FIG. 4

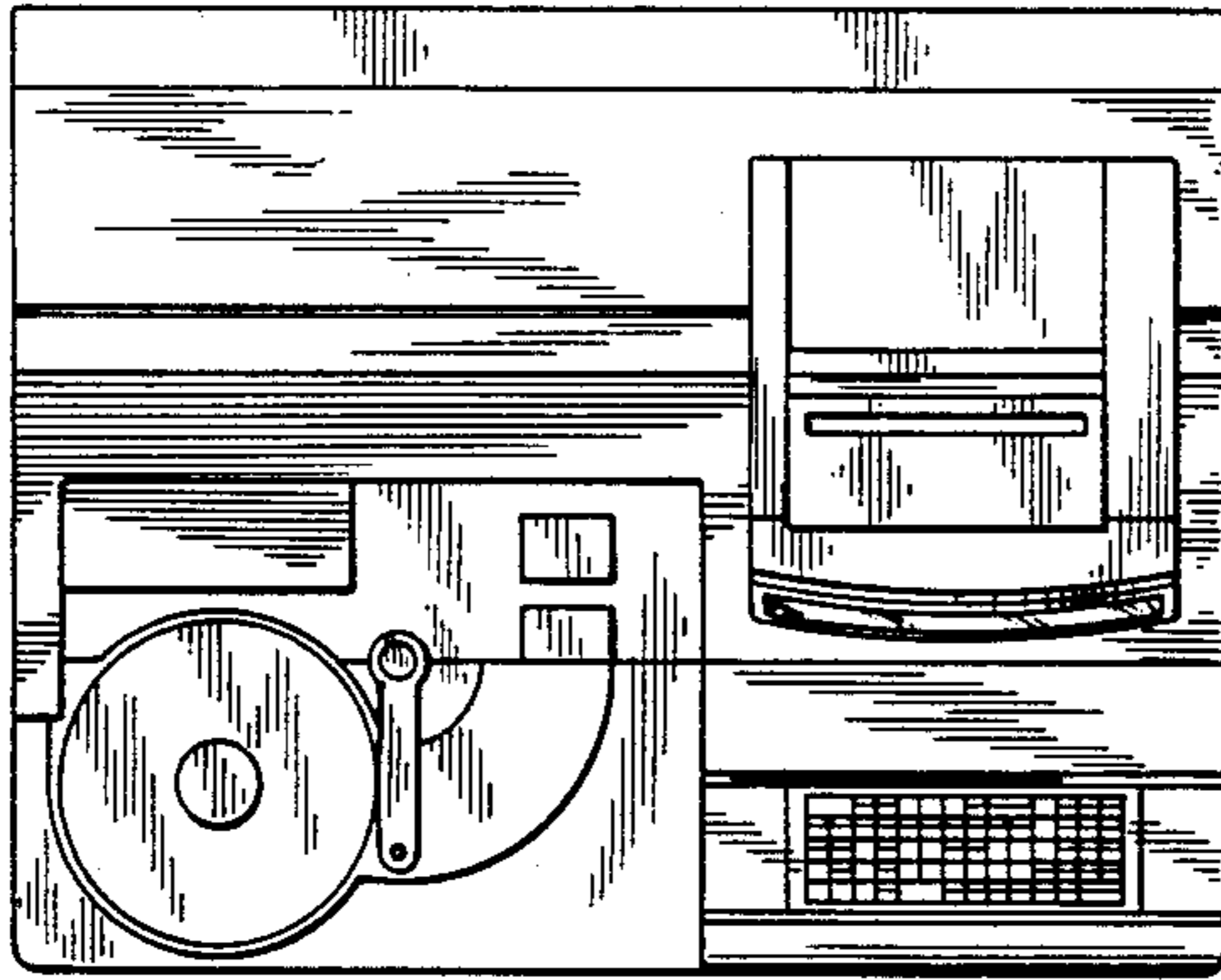


FIG. 5

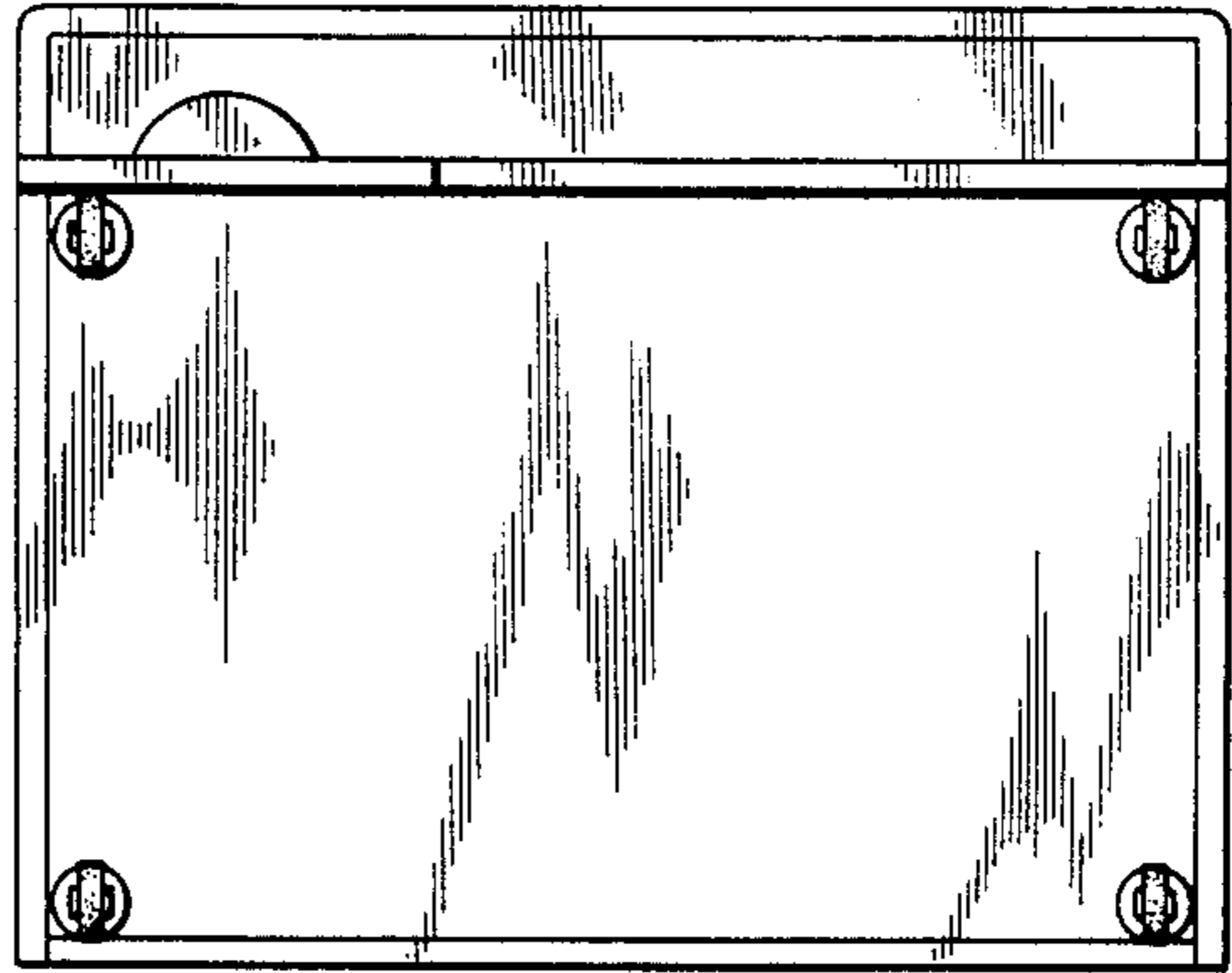


FIG. 6

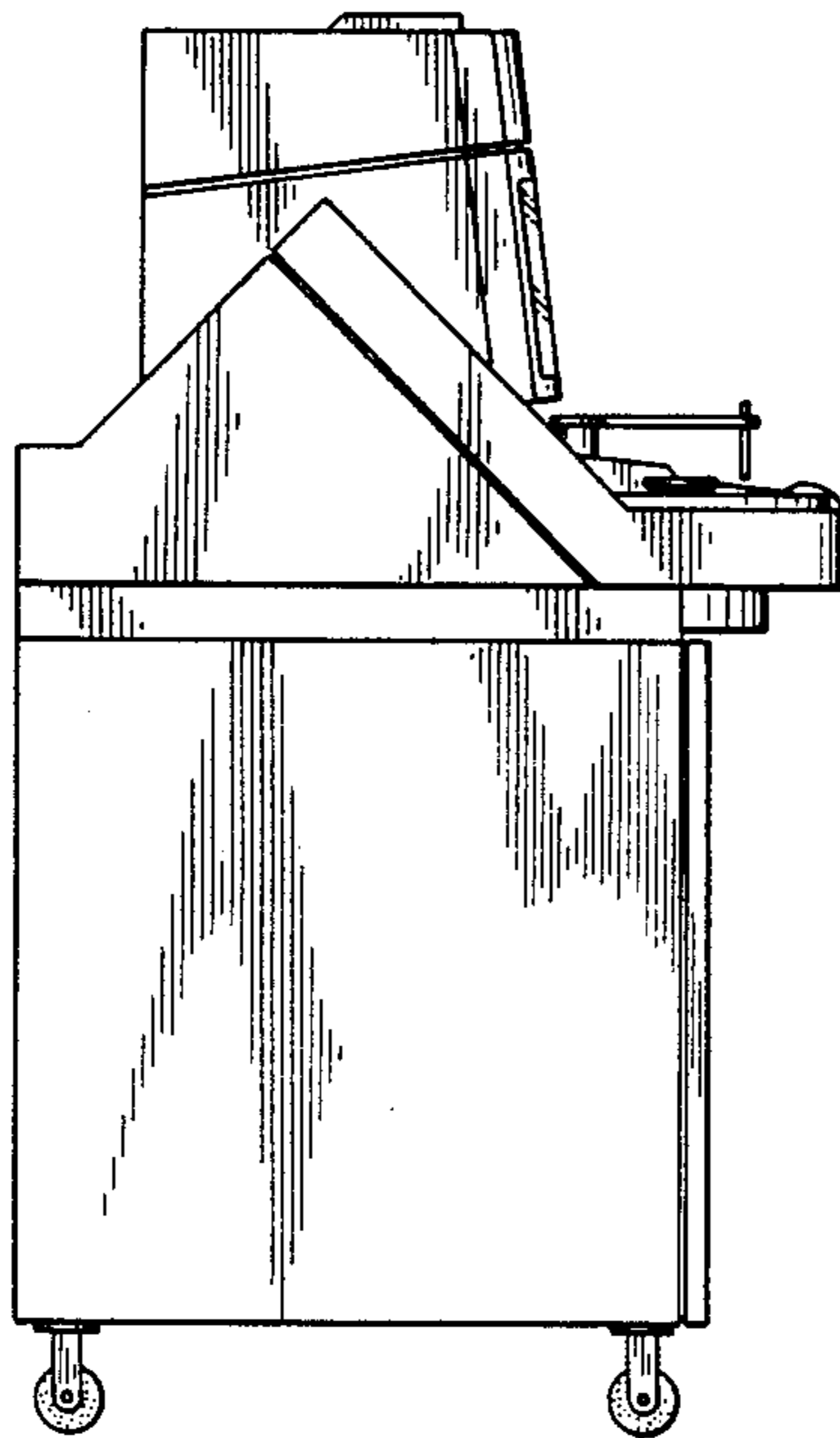


FIG. 7

